Signetics

FAST 74F379
Register

Quad Parallel Register With Enable

FAST Products

Product Specification

FEATURES

- **Edge-triggered D-type inputs**
- **Buffered positive edge-triggered clock**
- **Buffered common Enable input**
- **True and complementary outputs**

TYPE	TYPICAL f_{MAX}	TYPICAL SUPPLY CURRENT (TOTAL)
74F379	120MHz	28mA

DESCRIPTION

The 74F379 is a 4-bit register with buffered common Enable ($\overline{E}$). This device is similar to the 'F175 but features the common Enable rather common Master Reset.

ORDERING INFORMATION

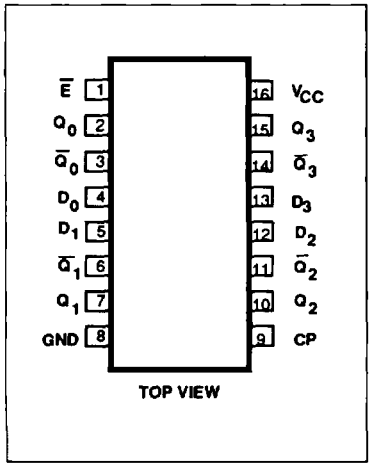
PACKAGES	COMMERCIAL RANGE V_{CC} = 5V±10%; T_A = 0°C to +70°C
16-Pin Plastic DIP	N74F379N
16-Pin Plastic SO	N74F379D

INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

PINS	DESCRIPTION	74F(U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
D_0 - D_3	Data inputs	1.0/1.0	20µA/0.6mA
$\overline{E}$	Enable input (active Low)	1.0/1.0	20µA/0.6mA
CP	Clock Pulse input (active rising edge)	1.0/1.0	20µA/0.6mA
Q_0 - Q_3	True outputs	50/33	1.0mA/20mA
$\overline{Q}_0$ - $\overline{Q}_3$	Complementary outputs	50/33	1.0mA/20mA

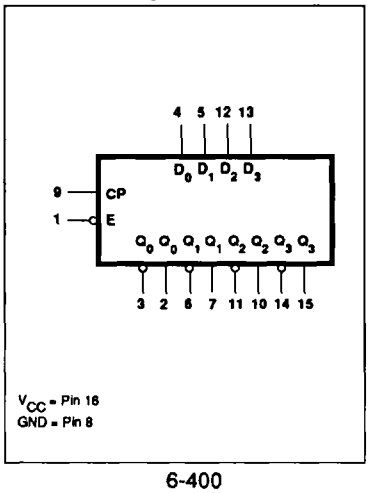
NOTE:
One (1.0) FAST Unit Load is defined as: 20µA in the High state and 0.6mA in the Low state.

PIN CONFIGURATION

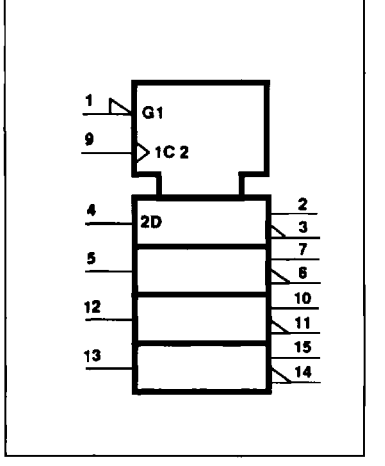


TOP VIEW

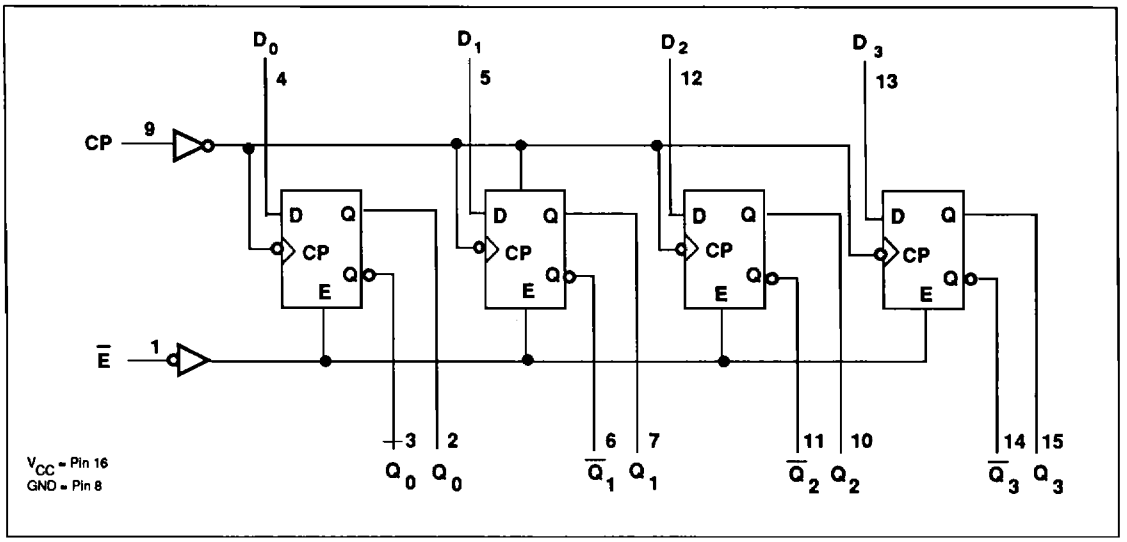
LOGIC SYMBOL



LOGIC SYMBOL(IEEE/IEC)



LOGIC DIAGRAM



FUNCTION TABLE

INPUTS			OUTPUTS	
$\overline{E}$	CP	D_n	Q_n	$\overline{Q}_n$
H	↑	X	NC	NC
L	↑	h	H	L
L	↑	l	L	H

H = High voltage level
h = High voltage level one set-up time prior to the Low-to-High clock transition
L = Low voltage level
l = Low voltage level one set-up time prior to the Low-to-High clock transition
X = Don't care
↑ = Low-to-High clock transition
NC = No change

ABSOLUTE MAXIMUM RATINGS

(Operation beyond the limits set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
V_{CC}	Supply voltage	-0.5 to +7.0	V
V_{IN}	Input voltage	-0.5 to +7.0	V
I_{IN}	Input current	-30 to +5	mA
V_{OUT}	Voltage applied to output in High output state	-0.5 to +V_{CC}	V
I_{OUT}	Current applied to output in Low output state	40	mA
T_A	Operating free-air temperature range	0 to +70	°C
T_{STG}	Storage temperature	-65 to +150	°C

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMITS			UNIT
		Min	Nom	Max	
V_{CC}	Supply voltage	4.5	5.0	5.5	V
V_{IH}	High-level input voltage	2.0			V
V_{IL}	Low-level input voltage			0.8	V
I_{IK}	Input clamp current			-18	mA
I_{OH}	High-level output current			-1	mA
I_{OL}	Low-level output current			20	mA
T_A	Operating free-air temperature range	0		70	°C

DC ELECTRICAL CHARACTERISTICS (Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER	TEST CONDITIONS[1]		LIMITS			UNIT
				Min	Typ[2]	Max	
V_{OH}	High-level output voltage	V_{CC} = MIN, V_{IL} = MAX	±10%V_{CC}	2.5			V
		V_{IH} = MIN, I_{OH} = MAX	±5%V_{CC}	2.7	3.4		V
V_{OL}	Low-level output voltage	V_{CC} = MIN, V_{IL} = MAX	±10%V_{CC}		0.30	0.50	V
		V_{IH} = MIN, I_{OL} = MAX	±5%V_{CC}		0.30	0.50	V
V_{IK}	Input clamp voltage	V_{CC} = MIN, I_I = I_{IK}			-0.73	-1.2	V
I_I	Input current at maximum input voltage	V_{CC} = MAX, V_I = 7.0V				100	µA
I_{IH}	High-level input current	V_{CC} = MAX, V_I = 2.7V				20	µA
I_{IL}	Low-level input current	V_{CC} = MAX, V_I = 0.5V				-0.6	mA
I_{OS}	Short circuit output current[3]	V_{CC} = MAX		-60		-150	mA
I_{CC}	Supply current (total)	V_{CC} = MAX, D_n=$\overline{E}$=4.5V, CP=↑			28	40	mA

NOTES:

1. For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.
2. All typical values are at V_{CC} = 5V, T_A = 25°C.
3. Not more than one output should be shorted at a time. For testing I_{OS}, the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

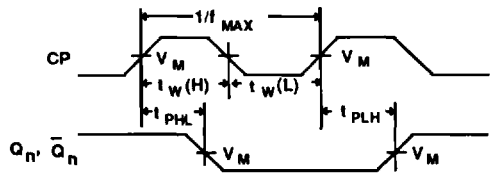
AC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	TEST CONDITION	LIMITS					UNIT
			T_A = +25°C, V_{CC} = 5V, C_L = 50pF, R_L = 500Ω			T_A = 0°C to +70°C, V_{CC} = 5V ±10%, C_L = 50pF, R_L = 500Ω		
			Min	Typ	Max	Min	Max	
f_{MAX}	Maximum clock frequency	Waveform 1	100	120		90		MHz
t_{PLH} t_{PHL}	Propagation delay CP to Q_n or $\overline{Q}_n$	Waveform 1	3.5 4.5	5.0 6.5	7.0 8.5	3.5 4.5	8.0 9.5	ns

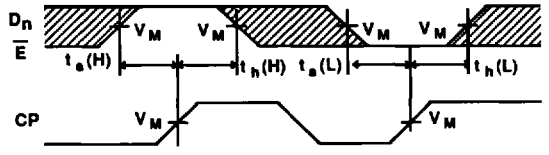
AC SETUP REQUIREMENTS

SYMBOL	PARAMETER	TEST CONDITION	LIMITS					UNIT
			T_A = +25°C, V_{CC} = 5V, C_L = 50pF, R_L = 500Ω			T_A = 0°C to +70°C, V_{CC} = 5V ±10%, C_L = 50pF, R_L = 500Ω		
			Min	Typ	Max	Min	Max	
$t_s(H)$ $t_s(L)$	Setup time, High or Low D_n to CP	Waveform 2	3.0 3.0			3.0 3.0		ns
$t_h(H)$ $t_h(L)$	Hold time, High or Low D_n to CP	Waveform 2	1.0 1.0			1.0 1.0		ns
$t_s(H)$ $t_s(L)$	Setup time, High or Low $\overline{E}$ to CP	Waveform 2	6.0 6.0			6.0 6.0		ns
$t_h(H)$ $t_h(L)$	Hold time, High or Low $\overline{E}$ to CP	Waveform 2	0.0 0.0			0.0 0.0		ns
$t_w(H)$ $t_w(L)$	CP Pulse width, High or Low	Waveform 1	4.0 5.0			4.0 5.0		ns

AC WAVEFORMS



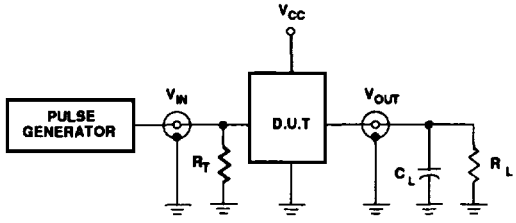
Waveform 1. Propagation Delay, Clock Input To Output, Clock Pulse Width, and Maximum Clock Frequency



Waveform 2. Data And Enable Setup And Hold Times

NOTE: For all waveforms, V_M = 1.5V.
The shaded areas indicate when the input is permitted to change for predictable output performance.

TEST CIRCUIT AND WAVEFORMS



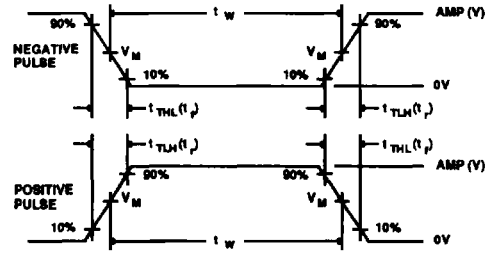
Test Circuit For Totem-Pole Outputs

DEFINITIONS

R_L = Load resistor; see AC CHARACTERISTICS for value.

C_L = Load capacitance includes jig and probe capacitance; see AC CHARACTERISTICS for value.

R_T = Termination resistance should be equal to Z_{OUT} of pulse generators.



V_M = 1.5V

Input Pulse Definition

FAMILY	INPUT PULSE REQUIREMENTS				
	Amplitude	Rep. Rate	t_W	t_{TLH}	t_{THL}
74F	3.0V	1MHz	500ns	2.5ns	2.5ns